

Application No.	Applicant(s)	
10/041,957	TEIG ET AL.	
Examiner	Art Unit	
Riph C Tot	2925	

SEARCHED					
Class	Subclass	Date	Examiner		
716	1-18	1/8/2005	ВТ		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST SEARCH	1/8/2005	ВТ	
IEEE	1/8/2005	ВТ	